Under the Paperwork Reduction Act of 1995. In ADEMARK TRANSMITTAL FORM (to be used for all correspondence after initial filling Total Number of Pages in This Submission	o persons are required to respond to a col Application Number Filing Date First Named Inventor Art Unit Examiner Name Attorney Docket Number	Patent and Trademark Office; U.S. DEPARTMENT OF COMMI Ilection of information unless it displays a valid OMB control nu 10/600904 06/20/2003 Robert Sigurd Nelson 2882 I rakli Kiknadze that apply)
Fee Transmittal Form Fee Attached Amendment/Reply After Final Affidavits/declaration(s) Extension of Time Request Express Abandonment Request Information Disclosure Statement Certified Copy of Priority Document(s) Reply to Missing Parts/ Incomplete Application Reply to Missing Parts under 37 CFR 1.52 or 1.53	Drawing(s) Licensing-related Papers Petition Petition to Convert to a Provisional Application Power of Attorney, Revocation Change of Correspondence A Terminal Disclaimer Request for Refund CD, Number of CD(s) Landscape Table on CD Remarks	After Allowance Communication to Appeal Communication to Board of Appeals and Interferences Appeal Communication to TC (Appeal Notice, Brief, Reply Brief) Proprietary Information Status Letter Other Enclosure(s) (please Identify below):
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Signature

Polest Sigurd Melson

Typed or printed name

Robert Sigurd Nelson

Date March 4, 2006

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Appl. No. : 10/600,904

Applicants: Robert Sigurd Nelson, William Bert Nelson

Filing Date: June 20, 2003 Examiner: Irakli Kiknadze

Art Unit : 2882

Title : DEVICE AND SYSTEM FOR IMPROVED IMAGING IN NUCLEAR

MEDICINE AND MAMMOGRAPHY

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

March 4, 2006

Dear Mr. Kiknadze:

In response to the Office Action post marked January 24, 2006, please see the following remarks for application 10/600,904.

REMARKS

In the office action post marked January 24, 2006 the Examiner accepted claim 59 and rejected claims 57, 58 based on Dobbs, Spitz, Kump, and Walters.

Applicants will address first the rejection of claim 57 as being anticipated by Dobbs (Pat. No. 5,444,752). Dobbs describes a means of compensating for the temperature-dependent response of a solid state detector used with a CT imaging system by exposing the detector to a broad-band (conventional) x-ray source and recording the detector response as the temperature of the detector is varied externally and thereby creating a temperature calibration table (col. 4, lines 30-33, column 6, lines 59-61 and 64-68). Dobbs' detector does not offer energy resolution but rather is a traditional integrating detector. Dobbs does not calibrate the energy spectrum of the x-ray beam as a function of position at the detector.

The inventors describe employing a x-ray detector capable of measuring the energies of photons. This means that the detector can measure not only how the intensity of the beam varies spatially but also the how the energy spectrum of the x-ray beam varies spatially. In other words, the intensity for each energy in the single x-ray beam spectrum can be measured as a function of spatial location of each detector pixel. This can be done with a single KVP x-ray beam. This single x-ray beam spectrum data set for each pixel is compared against the data set of energy and intensity acquired when imaging a patient with the same single x-ray beam spectrum. Using a detector with